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SEMICONDUCTOR THIN FILM (54) MANUFACTURE OF

(57) Abstract:

desirably, hydrogen. consisting of fluorosilane, silane or, discomposing a mixture gas single crystalline substrate by photoa single crystalline or amorphous thin film with superior orientation on PURPOSE: To form a semiconductor

crystallineor amorphous single CONSTITUTION: A single

age 2 of 4

or arsine (AsH3) is usable. dibolane (B2H6) is usable. As V is heated to 100W400°C under discharge means 6, and the substrate which has at least a light permiating placed in a thin film forming device 7 cleaned with washing or etching is crystalline substrate whose surface is group compounds, phosphine (PH3) to be added to the mixture gas, usable. As the III group compounds SimH2m+2 (integer of m=1W3) are disilane, trisilane expressed with fluorosilane being more than twice he former. As the fluorosilane, SiH4the flowing ratio of silane to is supplied to the said device, with vaccum discharge. The material gas introduction means 5 and a vaccum 3, a substrate heating means 4, a gas window 1, a substrate holding means usable. As the silane, monosilane, nFn(integer of n=1W3) or Si2F6 is flowing ratio of hydrogen to the fluorosilane being 0.5W50 and the

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